

<b>Notice of References Cited</b>	Application/Control No. 10/564,479		Applicant(s)/Patent Under Reexamination HEIMALA ET AL.	
	Examiner Mark L. Shevin		Art Unit 1793	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2004/050925 A1	06-2004	Finland	Hanniala et al	C22B 7/04
	O	WO 2006/084950 A1	08-2006	Finland	Hulthom et al	C22B 15/00
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#### NON-PATENT DOCUMENTS

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